

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/773,297	WALSH, THOMAS J.	
Examiner J. Derek Rütten		Art Unit 2122	Page 1 of 2	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,495,412 A	02-1996	Thiessen, Ernest M.	705/1
	B	US-5,706,452 A	01-1998	Ivanov, Vladimir I.	345/751
	C	US-6,154,753 A	11-2000	McFarland, Jonna A.	715/508
	D	US-6,381,610 B1	04-2002	Gundewar et al.	707/104.1
	E	US-6,574,578 B1	06-2003	Logan, Timothy Dennis	702/122
	F	US-6,604,131 B1	08-2003	Warris et al.	709/205
	G	US-6,584,569 B2	06-2003	Reshef et al.	713/201
	H	US-6,662,217 B1	12-2003	Godfrey et al.	709/219
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"IEEE Standard for Software Reviews and Audits", June 1989, IEEE Inc., IEEE Standard 1028-1988
	V	Paulk, Curtis, Chrissis, and Weber, "Capability Maturity Model, Version 1.1", July 1993, IEEE Software, Volume 10, Issue 4, pp. 18-27, ISSN: 0740-7459
	W	J.H. Baumert, "Process Assessment with a Project Focus", March 1994, IEEE Software, Volume 11, Issue 2, pp. 89-91, ISSN: 0740-7459
	X	R.C. Smith, "Software Development Process Standards: Challenges for Process Assurance", June 1997, Third IEEE International Software Engineering Standards Symposium and Forum, ISESS 97, pp. 180-186

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"IEEE Standard for Software Quality Assurance Plans", June 1998, IEEE Inc., IEEE Standard 730-1998, ISBN 0-7381-0328-4
	V	P. Runeson and P. Isacsson, "Software Quality Assurance - Concepts and Misconceptions", August 1998, Proceedings of the 24th Euromicro Conference, Volume 2, pp. 853-859
	W	Mark Paulk, "Using the Software CMM with Good Judgment", 1999, ASQ Software Quality Professional, Volume 1, Number 3, pp. 19-29
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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